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Quick Tips

 Enter your search terms in <u>lower case</u> with a space between the terms.

sales offices

You can also enter a full question or concept in plain language.

Where are the sales offices?

 Capitalize <u>proper nouns</u> to search for specific people, places, or products.

John Colter, Netscape Navigator

Enclose a phrase in double quotes to search for that exact phrase.

"museum of natural history" "museum of modern art"

• Narrow your searches by using a + if a search term <u>must appear</u> on a page.

museum +art

• Exclude pages by using a - if a search term <u>must not appear</u> on a page.

museum -Paris

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museum +"natural history" dinosaur -Chicago

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» Key

IEEE JNL IEEE Journal or

Magazine

IET JNL

IET Journal or Magazine IEEE Conference

IEEE CNF

Proceeding

IET CNF

IET Conference

Proceeding

IEEE STD IEEE Standard

1. Linearization of large-signal scattering functions

Verspecht, J.; Williams, D.F.; Schreurs, D.; Remley, K.A.; McKinley, M.D.;

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Microwave Theory and Techniques, IEEE Transactions on

Volume 53, issue 4, Part 1, April 2005 Page(s):1369 - 1376

Digital Object Identifier 10.1109/TMTT.2005.845771

AbstractPlus | References | Full Text: PDF(448 KB) | IEEE JNL

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2. Black box modelling of hard nonlinear behavior in the frequency domain

Verspecht, J.; Schreurs, D.; Barel, A.; Nauwelaers, B.;

Microwave Symposium Digest, 1996., IEEE MTT-S International

Volume 3, 17-21 June 1996 Page(s):1735 - 1738 vol.3 Digital Object Identifier 10.1109/MWSYM.1996.512277

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3. Accurate spectral estimation based on measurements with a distorted-timebase digitizer

Verspecht, J.;

Instrumentation and Measurement Technology Conference, 1993. IMTC/93. Conference

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18-20 May 1993 Page(s):699 - 704

Digital Object Identifier 10.1109/IMTC.1993.382553

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